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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/049,792	02/14/2002	Hironori Aoki	Hironori Aoki 542-007-2			
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WARE FRE	SSOLA VAN DER SLI	EXAMINER				
ADOLPHSON, LLP BRADFORD GREEN BUILDING 5			DUONG, THOI V			
755 MAIN STREET, P O BOX 224 MONROE. CT 06468			ART UNIT	PAPER NUMBER		
			2871			

DATE MAILED: 08/29/2002

Please find below and/or attached an Office communication concerning this application or proceeding.

•		Application I	No.	Applicant(s)					
		10/049,792		AOKI, HIRONORI	14				
Office Action Summar		Examiner		Art Unit	-				
•		hoi V Duong		2871	•				
	The MAILING DATE of this communication appears on the cover sheet with the correspondence address								
Period for Reply									
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE <u>03</u> MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). - Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).									
Status									
· 									
<i>,</i> —	This action is FINAL . 2b)⊠ This action is non-final.								
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213. Disposition of Claims									
4) Claim(s) 1-21 is/are pending in the application.									
4a) Of the above claim(s) is/are withdrawn from consideration.									
5) Claim(s) is/are allowed.									
6)⊠ Claim(s) <u>1-21</u> ⊯/are rejected.									
7) Claim(s) is/are objected	to.								
8) Claim(s) are subject to r	estriction and/or e	lection requ	ıirement.						
Application Papers									
9) The specification is objected to	_	_							
10)☐ The drawing(s) filed on is									
Applicant may not request that a	-								
11) The proposed drawing correctio				ived by the Examine	r.				
If approved, corrected drawings are required in reply to this Office action.									
12) The oath or declaration is objected to by the Examiner.									
Priority under 35 U.S.C. §§ 119 and 120									
13)⊠ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a)⊠ All b)□ Some * c)□ None of:									
		navo boon r	oceived						
	1. Certified copies of the priority documents have been received.								
2. Certified copies of the priority documents have been received in Application No									
 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 									
14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).									
a) ☐ The translation of the foreign language provisional application has been received. 15)☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.									
Attachment(s)									
Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Rev Information Disclosure Statement(s) (PTO-1)		4) 5) . 6)	Notice of Informal	y (PTO-413) Paper No(Patent Application (PTC					

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DETAILED ACTION

Claim Objections

1. Claim 10 is objected to because of the following informalities: on page 43, line 20, "corrected" should be --collected--. Appropriate correction is required.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 1-12 and 14-21 are rejected under 35 U.S.C. 102(b) as being anticipated by Dohjo et al. (USPN 6,078366).

As shown in Figs. 1, 5 and 13, Dohjo discloses an array substrate 100 (as well as a manufacturing method for the array substrate) comprising:

- a display area (TFT region) in which pixel electrodes 131 are formed,
- a scanning line 111 arranged between the pixel electrodes,
- a signal line 110 crossing over the scanning line interposing an insulating layer 115 therebetween,
 - a terminal 152 to which a scanning signal is applied, and
- an extended scanning line125a formed from a conductive film for connecting the scanning line with the terminal,

wherein the conductive film for the extended scanning line and that for the scanning line are of different layers;

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wherein the extended scanning line 125a and the signal line 110 are formed from the conductive film of same layer;

wherein the extended scanning line is electrically connected to the scanning line through contact holes 153, 154 at the neighborhood of the display area and electrically connected to the terminal for the scanning signal through contact holes 155, 156 at the neighborhood of the terminal;

wherein aluminum or aluminum alloy is used for material of the scanning line (col. 7, lines 16-27);

wherein high melting point metal such as Cr or Mo is used for material of the signal line (col. 7, lines 28-37);

wherein the scanning line and the extended scanning line are electrically connected via a conductive film of the same layer 131 as that for the pixel electrode;

wherein liquid crystal is interposed between the array substrate and a counter substrate 200 having a common electrode 231 and a color filter 221;

wherein the extended scanning line 125a is formed in a grid like shape at a region in which the scanning line and the extended scanning line are overlapped within a connecting portion between the scanning line and the extended scanning line (see Fig. 13).

As shown in Figs. 28-31, the array substrate further comprises:

an auxiliary capacitance line 113 arranged in parallel to the scanning line,
a collected auxiliary capacitance line (dotted line of 190) arranged in parallel to
the signal line and electrically connected to the auxiliary capacitance line,

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a terminal to which a common signal is applied (at left of Fig. 28), and an extended auxiliary capacitance line 125 formed from a conductive film for connecting the collected auxiliary capacitance line with the terminal for the common signal,

wherein the conductive film for the extended auxiliary capacitance line and that for the collected auxiliary capacitance line are of different layers (col. 23, lines 46-67; col. 24, lines 1-13);

wherein the extended auxiliary capacitance line and the signal line are formed from the conductive film of same layer and the extended auxiliary capacitance line is electrically connected to the collected auxiliary capacitance line at the neighborhood of the display area through a contact hole 192 and electrically connected to the terminal for the common signal through a contact hole 194 at the neighborhood of the terminal;

wherein the auxiliary capacitance line, the corrected auxiliary capacitance line and the scanning line are formed from the conductive film of same layer.

wherein the collected auxiliary capacitance line and the extended scanning line are crossing interposing a insulating layer 117 therebetween (see Fig. 28);

wherein the collected auxiliary capacitance line and the extended auxiliary capacitance line are electrically connected via a conductive film 193 of the same layer as that for the pixel electrode.

wherein the extended auxiliary capacitance line 125 is formed in a grid or ladder like shape at a region in which the collected auxiliary capacitance line and the extended auxiliary capacitance line are overlapped within a connecting portion between the

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collected auxiliary capacitance line and the extended auxiliary capacitance line (see Fig. 31)

Dohjo also discloses in another embodiment that the extended scanning line and the pixel electrodes are formed from the conductive film of same layer (col. 5, lines 27-45). Since the extended auxiliary capacitance line is formed at the same layer as the extended scanning line, the extended auxiliary capacitance line and the pixel electrodes are formed from the conductive film of same layer.

Claim Rejections - 35 USC § 103

- 4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 5. Claim 13 is rejected under 35 U.S.C. 103(a) as being unpatentable over Dohjo in view of Sakata et al. (JP 11-284195).

Dohjo discloses an array substrate that is basically the same as that recited in Claim 13 except that the material used for the scanning line is not nitridated aluminum or nitridated aluminum alloy. Sakata discloses a process in which impurity constituted of one of N, O, Si and C is added to an upper layer of a scanning line formed of pure aluminum or aluminum alloy to directly provide low contact resistance (paragraph 11). Thus, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the array substrate of Dohjo with the teaching of Sakata

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by using partly or whollynitridated aluminum or partly or wholly nitridated aluminum alloy for the scanning lines so as to obtain a good contact resistance.

Conclusion

- 6. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.
- 7. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Thoi V. Duong whose telephone number is (703) 308-3171. The examiner can normally be reached on Monday-Friday from 8:00 am to 4:30 pm.

Thoi Duong

08/25/2002

James a. Jucke

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